

INFORMATION DISCLOSURE
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APPLICATION

(PTO-1449)

ATTY. DOCKET NO.
KPO-003

U.S. PATENT
APPLICATION NO.
10/588,007

APPLICANT
Naoto HIROSAKI et al.

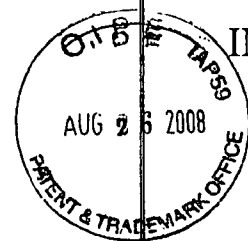
FILING DATE
August 17, 2006

GROUP
2879

U.S. PATENT DOCUMENTS

EXAMINER'S INITIALS	PATENT NO.	DATE	NAME	CLASS	SUBCLASS	FILING DATE
	US 6,717,355 (JP 2002-76434)	04/06/2004	Yuji TAKAHASHI et al.			08/27/2001
	US 2003/030036 (JP 2002-363554)	02/13/2003	Mamoru MITOMO et al.			06/06/2002
	US 2003/0030368 (JP 2003-124527)	02/13/2003	Andries ELLENS et al.			07/03/2002
	US 6,674,233 (JP 2003-203504)	01/06/2004	Andries ELLENS et al.			07/18/2002
	US 2003/094893 (JP 2003-206481)	05/22/2003	Andries ELLENS et al.			07/26/2002
	6,632,379	10/14/03	Mitomo et al.			
	6,776,927	8/17/04	Mitomo et al.			
	6,670,748	12/30/03	Ellens et al.			
	6,724,142	4/20/04	Ellens et al.			
	US 2004/0135504	7/15/04	Tamaki et al.			
	6,682,863	1/27/04	Bolty et al.			
	US 2005/0189863	9/1/05	Nagatomi et al.			
	US 2006/0033083	2/16/06	Sukane et al.			
	US 2006/0038477	2/23/06	Tamaki et al.			
	US 2006/0078883	4/13/06	Himaki et al.			
	2006/0017385	01/26/06	A. NAGATOMI et al			
	2006/0006782	01/12/06	A. NAGATOMI et al			
	2006/0043337	03/02/06	K. SAKANE et al			
	2006/0065878	03/30/06	K. SAKANE et al			
	2006/0045832	03/02/06	A. NAGATOMI et al			
	2006/0091790	05/04/06	A. NAGATOMI et al			
	2006/0022573	02/02/06	M. GOTOH et al			
	2007/0029525	02/08/07	M. GOTOH et al			
	2006/0197432	09/07/06	A. NAGATOMI et al			

ALL REFERENCES CONSIDERED EXCEPT WHERE LINED THROUGH. /PM/



FOREIGN PATENT DOCUMENTS							
EXAMINER'S INITIALS	PATENT NO.	DATE	COUNTRY	CLASS	SUBCLASS	Translation	
						Yes	No
	2005-8793	1/13/2005	Japan				
	2005-8794	1/13/2005	Japan				
	2003-336059	11/28/2003	Japan				
	2004-277663	10/7/2004	Japan				
	2004-67837	3/4/2004	Japan				
	EP 1264 873 A2	12/11/2002	Europe				
	EP 1 278 250 A2	1/22/2003	Europe				
	DE 101 33 352 A1	2/6/2003	Germany				
	EP 1 296 383 A2	3/26/2003	Europe				
	DE 101 46 719 A1	4/17/2003	Germany				
	EP 1 296 376 A2	3/26/2003	Europe				
	DE 101 47 040 A1	4/24/2003	Germany				
	WO 2005/103199	11/3/05	Japan				
	2002-322474	11/8/02	Japan w/ English abstract				
	2003-277746	10/2/03	Japan w/ English abstract				
	2004-010786	1/15/04	Japan w/ English abstract				
	2004-182780	7/2/04	Japan w/ English abstract				
	2004-182781	7/2/04	Japan w/ English abstract				
	2004-189996	7/8/04	Japan w/ English abstract				
	2006-028295	02/02/06	JAPAN (English abstract				
	2006-063286	03/09/06	JAPAN (English abstract				
	2006-070109	03/16/06	JAPAN (English abstract				
OTHER ART (Including Author, Title, Date, Pertinent Pages, Etc.)							
	Zhan-Kun HUANG, et al., "Phase relations of the Si_3N_4 -AlN-CaO system", JOURNAL OF 4, 1985, page 255-259						
	H.A. Hoeppe, et al. "Luminescence in Eu^{2+} -doped $Ba_2Si_5N_8$: fluorescence, thermoluminescence, and up ;Journal of Physics and Chemistry of Solids 61; 2000; pp. 2001-2006						
	J.W.H. van Kreveld "On new rare-earth doped M-Si-Al-O-N materials"; TU Eindhoven; 2000; pp. 1-173						
EXAMINER			DATE CONSIDERED				
/Peter Macchiarolo/			09/28/2008				

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